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Terms	Documents
l10 and l11	174

Database:

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- Derwent World Patents Index
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L12

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Set Name Query

side by side

*DB=USPT; PLUR=YES; OP=OR*L12 l10 and l11L11 l1 and l6L10 measur?L9 l1 and l5L8 planarized featureL7 l1 and l4L6 semiconductor and waferL5 l1 and l3L4 plan?L3 l1 and l2L2 planar?L1 ((356/237.1 |356/237.2 |356/237.3 |356/237.4 |356/237.5)!.CCLS.)**Hit Count Set Name**

result set

174 L12425 L11353850 L100 L91383019 L8769 L777162 L60 L5831699 L40 L3165 L21376 L1

END OF SEARCH HISTORY

Set Name Query

side by side

*DB=USPT; PLUR=YES; OP=OR*L14 l12 and l13L13 ellipsometricL12 l10 and l11L11 l1 and l6L10 measur?L9 l1 and l5L8 planarized featureL7 l1 and l4L6 semiconductor and waferL5 l1 and l3L4 plan?L3 l1 and l2L2 planar?L1 ((356/237.1 |356/237.2 |356/237.3 |356/237.4 |356/237.5)!.CCLS.)Hit Count Set Name

result set

8 L14558 L13174 L12425 L11353850 L100 L91383019 L8769 L777162 L60 L5831699 L40 L3165 L21376 L1

END OF SEARCH HISTORY